

Search Notes

Application/Control No.

10/754,572

Examiner

CHRIS C. CHU

Applicant(s)/Patent under
Reexamination

HONG ET AL.

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	E29.147, E27.111 & E21.19	4/11/2008	C.C.
257	E23.017	4/11/2008	C.C.
257	E29.137	4/11/2008	C.C.
257	E29.151	4/11/2008	C.C.
257	784 & 763	4/11/2008	C.C.
257	72 & 59	4/11/2008	C.C.
257	765	4/11/2008	C.C.
349	42 & 139	4/11/2008	C.C.
349	147 & 46	4/11/2008	C.C.
438	30 & 149	4/11/2008	C.C.
438	151	4/11/2008	C.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
As same	as above	4/11/2008	C.C.

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; and IBM_TDB;	4/11/2008	C.C.
Considered the references cited in the U.S. Pat. No.6,696,324	4/11/2008	C.C.